

## Jan<mark>uary 1996</mark>

## Features

- Devices QML Qualified in Accordance with MIL-PRFF-38535
- Detailed Electrical and Screening Requirements are Contained in SMD# 5962-96713 and Intersil's QM Plan
- 1.25 Micron Radiation Hardened SOS CMOS
- Total Dose
  Sook RAD (Si)
- Single Event Upset (SEU) Immunity: <1 x 10<sup>-10</sup> Errors/Bit/Day (Typ)

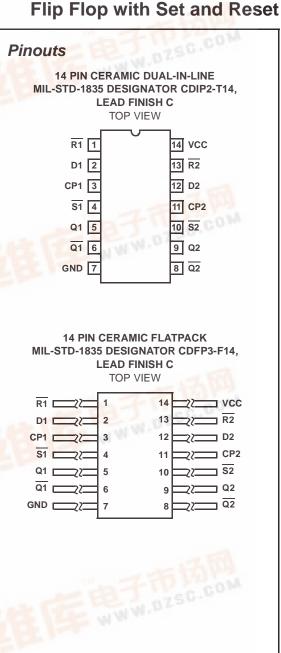
- Latch-Up Free Under Any Conditions
- Military Temperature Range ......-55°C to +125°C
- Significant Power Reduction Compared to ALSTTL Logic
- DC Operating Voltage Range ..... 4.5V to 5.5V
- Input Logic Levels
  - VIL = 0.8V Max
  - VIH = VCC/2 Min
- Input Current  $\leq$  1µA at VOL, VOH
- Fast Propagation Delay..... 20ns (Max), 13ns (Typ)

## Description

The Intersil ACTS74MS is a Radiation Hardened Dual D Flip Flop with Set(s) and Reset (R). The logic level at data input is transferred to the output during the positive transition of the clock. The Set and Reset are independent from the clock and accomplished by a low level on the appropriate input.

The ACTS74MS utilizes advanced CMOS/SOS technology to achieve high-speed operation. This device is a member of a radiation hardened, high-speed, CMOS/SOS Logic Family.

The ACTS74MS is supplied in a 14 lead Ceramic Flatpack (K suffix) or a 14 Lead Ceramic Dual-In-Line Package (D suffix).



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ACTS74MS

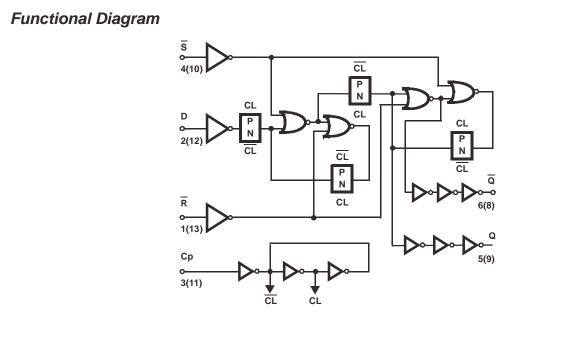
**Radiation Hardened Dual D** 

### Ordering Information

PART NUMBER	TEMPERATURE RANGE	SCREENING LEVEL	PACKAGE	
5962F9671301VCC	-55°C to +125°C	MIL-PRF-38535 Class V	14 Lead SBDIP	
5962F9671301VXC	-55°C to +125°C	MIL-PRF-38535 Class V	14 Lead Ceramic Flatpack	
ACTS74D/Sample	25°C	Sample	14 Lead SBDIP	
S74K/Sample	25°C	Sample	14 Lead Ceramic Flatpack	
ACTS74HMSR	25°C	Die	Die	

LITION: These devices are constitue to electrostatic discharge: follow proper IC Handling Procedure

E4070



#### TRUTH TABLE

	INP	OUTPUTS				
SET	RESET	СР	D	Q	Q	
L	Н	Х	Х	Н	L	
Н	L	Х	Х	L	Н	
L	L	Х	Х	H (Note 2)	H (Note 2)	
Н	Н		Н	Н	L	
Н	Н		L	L	Н	
Н	Н	L	Х	Q0	Q0	
H = High Level (Steady State) X = Don't Care						

L = Low Level (Steady State)

= Transition from Low to High Level

NOTES:

1. Q0 = the level of Q before the indicated input conditions were established.

2. This configuration is nonstable, that is, it will not persist when set and reset inputs return to their inactive (high) level.

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## **Die Characteristics**

#### DIE DIMENSIONS:

88 mils x 88 mils 2240mm x 2240mm

#### **METALLIZATION:**

Type: AlSi Metal 1 Thickness: 7.125kÅ ±1.125kÅ Metal 2 Thickness: 9kÅ ±1kÅ

#### **GLASSIVATION:**

Type: SiO<sub>2</sub> Thickness: 8kÅ ±1kÅ

# WORST CASE CURRENT DENSITY:

<2.0 x 10<sup>5</sup>A/cm<sup>2</sup>

## BOND PAD SIZE:

110μm x 110μm 4.3 mils x 4.3 mils

## Metallization Mask Layout

